



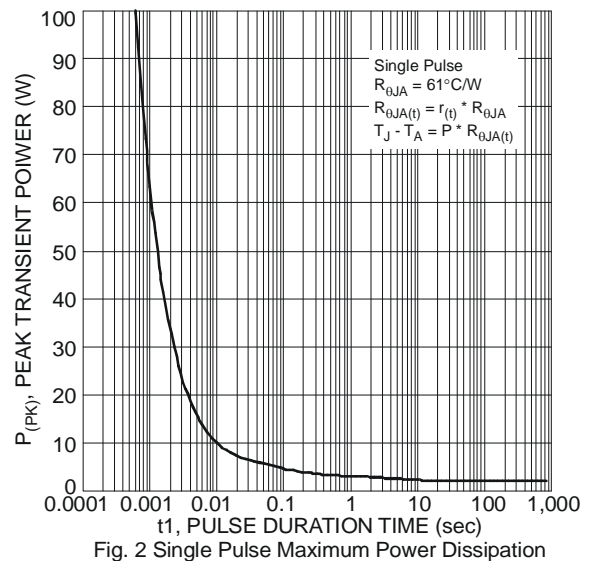
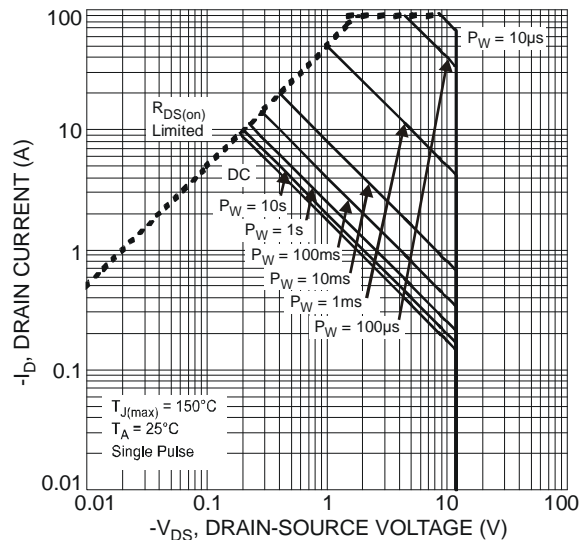
## Maximum Ratings (@T<sub>A</sub> = +25°C, unless otherwise specified.)

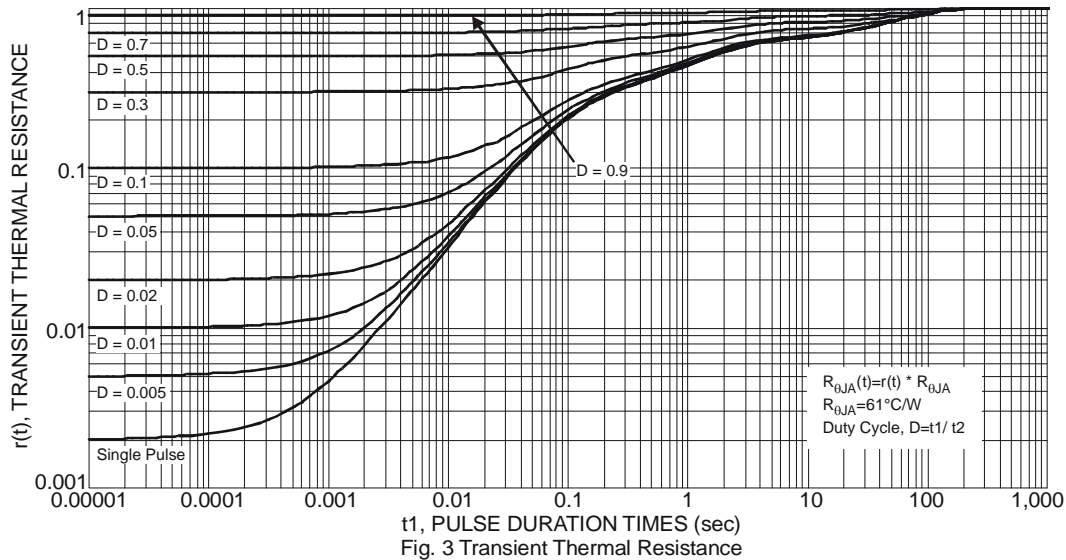
Characteristic			Symbol	Value	Units
Drain-Source Voltage			V <sub>DSS</sub>	-12	V
Gate-Source Voltage			V <sub>GSS</sub>	±8	V
Continuous Drain Current (Note 6) V <sub>GS</sub> = -4.5V	Steady State	T <sub>A</sub> = +25°C T <sub>A</sub> = +70°C	I <sub>D</sub>	-9.1 -7.2	A
	t < 5s	T <sub>A</sub> = +25°C T <sub>A</sub> = +70°C	I <sub>D</sub>	-11.2 -9.0	A
Pulsed Drain Current (10μs pulse, duty cycle = 1%)			I <sub>DM</sub>	-90	A
Continuous Source-Drain Diode Current		T <sub>A</sub> = +25°C T <sub>C</sub> = +25°C	I <sub>S</sub>	-2.5 -7.1	A
Pulsed Source-Drain Diode Current (10μs pulse, duty cycle = 1%)			I <sub>SM</sub>	-50	A

## Thermal Characteristics

Characteristic		Symbol	Value	Units
Total Power Dissipation (Note 5)	T <sub>A</sub> = +25°C	P <sub>D</sub>	0.66	W
	T <sub>A</sub> = +70°C		0.42	
Thermal Resistance, Junction to Ambient (Note 5)	Steady state	R <sub>θJA</sub>	189	°C/W
	t < 5s		123	
Total Power Dissipation (Note 6)	T <sub>A</sub> = +25°C	P <sub>D</sub>	2.03	W
	T <sub>A</sub> = +70°C		1.3	
Thermal Resistance, Junction to Ambient (Note 6)	Steady state	R <sub>θJA</sub>	61	°C/W
	t < 5s		40	
Thermal Resistance, Junction to Case (Note 6)	Steady state	R <sub>θJC</sub>	9.3	°C/W
Operating and Storage Temperature Range		T <sub>J</sub> , T <sub>STG</sub>	-55 to +150	°C

- Notes: 5. Device mounted on FR-4 PC board, with minimum recommended pad layout, single sided.  
6. Device mounted on FR-4 substrate PC board, 2oz copper, with thermal vias to bottom layer 1inch square copper plate





### Electrical Characteristics (@T<sub>A</sub> = +25°C, unless otherwise specified.)

Characteristic	Symbol	Min	Typ	Max	Unit	Test Condition
OFF CHARACTERISTICS (Note 7)						
Drain-Source Breakdown Voltage	BV <sub>DSS</sub>	-12	—	—	V	V <sub>GS</sub> = 0V, I <sub>D</sub> = -250μA
Zero Gate Voltage Drain Current T <sub>J</sub> = +25°C	I <sub>DSS</sub>	—	—	-1	μA	V <sub>DS</sub> = -12V, V <sub>GS</sub> = 0V
Gate-Source Leakage	I <sub>GSS</sub>	—	—	±2	μA	V <sub>GS</sub> = ±5V, V <sub>DS</sub> = 0V
ON CHARACTERISTICS (Note 7)						
Gate Threshold Voltage	V <sub>GS(th)</sub>	-0.35	—	-0.8	V	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = -250μA
V <sub>GS(th)</sub> Temperature Coefficient	Δ V <sub>GS(th)</sub> / Δ T <sub>J</sub>	-	2.5	—	mV/°C	I <sub>D</sub> = -250μA
On-State Drain Current	I <sub>D(ON)</sub>	-10	—	—	A	V <sub>GS</sub> = -4.5V, V <sub>DS</sub> < -5A
Static Drain-Source On-Resistance	R <sub>DS (ON)</sub>	—	12	16	mΩ	V <sub>GS</sub> = -4.5V, I <sub>D</sub> = -8.2A
			15	21.5		V <sub>GS</sub> = -2.5V, I <sub>D</sub> = -7.2A
			20	26		V <sub>GS</sub> = -1.8V, I <sub>D</sub> = -6.6A
			23	32		V <sub>GS</sub> = -1.5V, I <sub>D</sub> = -1A
			46	95		V <sub>GS</sub> = -1.2V, I <sub>D</sub> = -1A
Forward Transfer Admittance	Y <sub>fs</sub>	—	12	-	S	V <sub>DS</sub> = -4V, I <sub>D</sub> = -8.2A
Diode Forward Voltage	V <sub>SD</sub>	—	-0.8	-1.2	V	V <sub>GS</sub> = 0V, I <sub>S</sub> = -8A
DYNAMIC CHARACTERISTICS (Note 8)						
Input Capacitance	C <sub>iss</sub>	—	2953	—	pF	V <sub>DS</sub> = -4V, V <sub>GS</sub> = 0V, f = 1.0MHz
Output Capacitance	C <sub>oss</sub>	—	756	—		
Reverse Transfer Capacitance	C <sub>rss</sub>	—	678	—		
Gate Resistance	R <sub>g</sub>	—	8.6	18	Ω	V <sub>DS</sub> = 0V, V <sub>GS</sub> = 0V, f = 1MHz
Total Gate Charge	Q <sub>g</sub>	—	28.4	42.6	nC	V <sub>GS</sub> = -5V, V <sub>DS</sub> = -4, I <sub>D</sub> = -10A
Total Gate Charge	Q <sub>g</sub>	—	25.3	38		
Gate-Source Charge	Q <sub>gs</sub>	—	2.3	—		
Gate-Drain Charge	Q <sub>gd</sub>	—	7.2	—		
Turn-On Delay Time	t <sub>D(on)</sub>	—	20	30	ns	V <sub>DS</sub> = -4V, V <sub>GS</sub> = -4.5V, R <sub>G</sub> = 1Ω, R <sub>L</sub> = 0.4Ω, I <sub>D</sub> = -9.8A
Turn-On Rise Time	t <sub>r</sub>	—	28	42		
Turn-Off Delay Time	t <sub>D(off)</sub>	—	117	176		
Turn-Off Fall Time	t <sub>f</sub>	—	93	139		
BODY DIODE CHARACTERISTICS						
Diode Forward Voltage	V <sub>SD</sub>	—	-0.8	-1.2	V	V <sub>GS</sub> = 0V, I <sub>S</sub> = -9.8A
Continuous Source-Drain Diode Current (Note 6)	I <sub>S</sub>	—	—	-2.5	A	T <sub>A</sub> = +25°C
		—	—	-7.1		T <sub>C</sub> = +25°C
Pulse Diode Forward Current (Note 8)	I <sub>SM</sub>	—	—	-50		—
Body Diode Reverse Recovery Time (Note 8)	t <sub>rr</sub>	—	28	56	ns	I <sub>S</sub> = -9.8A, dI/dt = 100A/μs
Reverse Recovery Fall Time	t <sub>a</sub>	—	10	—		
Reverse Recovery Rise Time	t <sub>b</sub>	—	18	—		
Body Diode Reverse Recovery Charge (Note 8)	Q <sub>rr</sub>	—	13	26	nC	

Notes: 7. Short duration pulse test used to minimize self-heating effect  
8. Guaranteed by design. Not subject to production testing

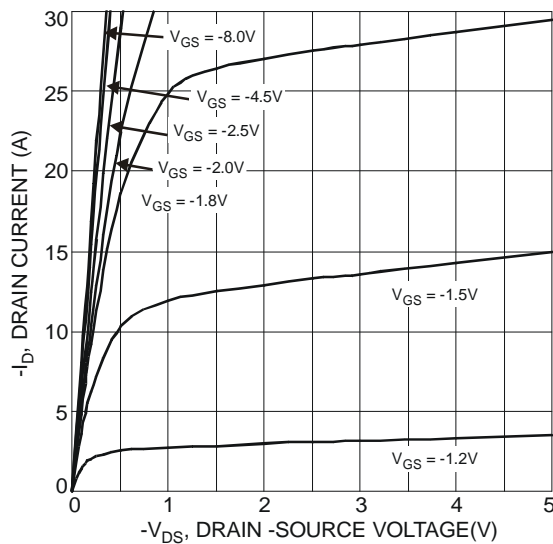


Fig. 4 Typical Output Characteristics

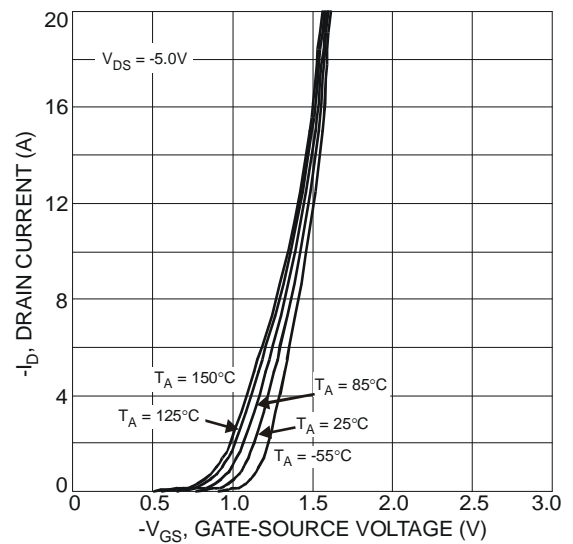


Fig. 5 Typical Transfer Characteristics

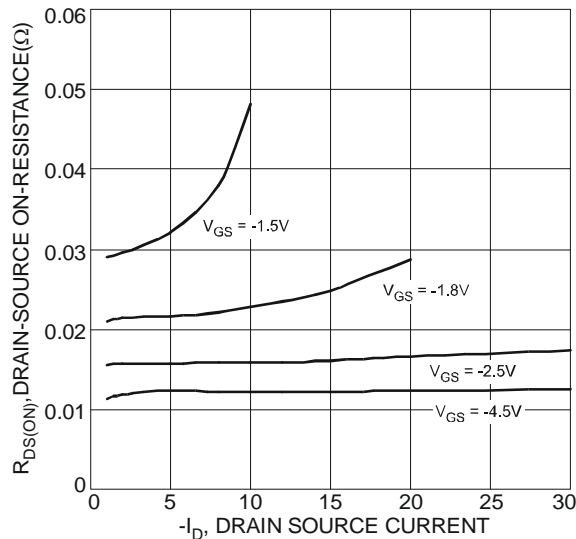


Fig. 6 Typical On-Resistance vs. Drain Current and Gate Voltage

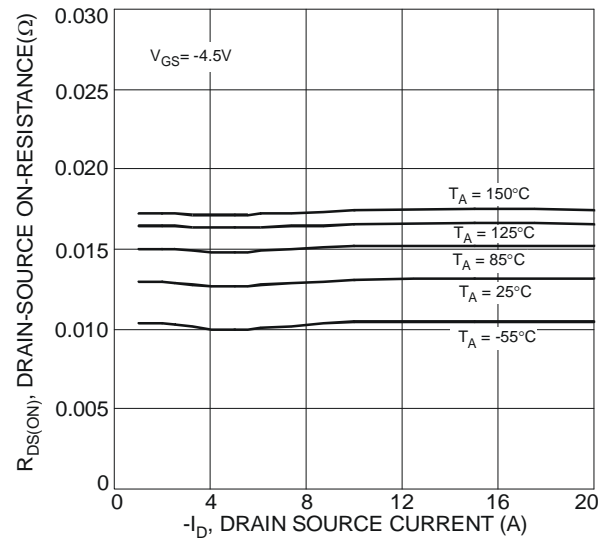


Fig. 7 Typical On-Resistance vs. Drain Current and Temperature

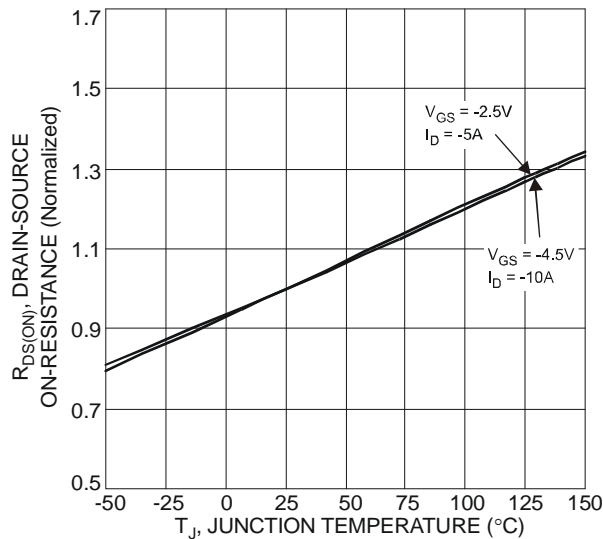


Fig. 8 On-Resistance Variation with Temperature

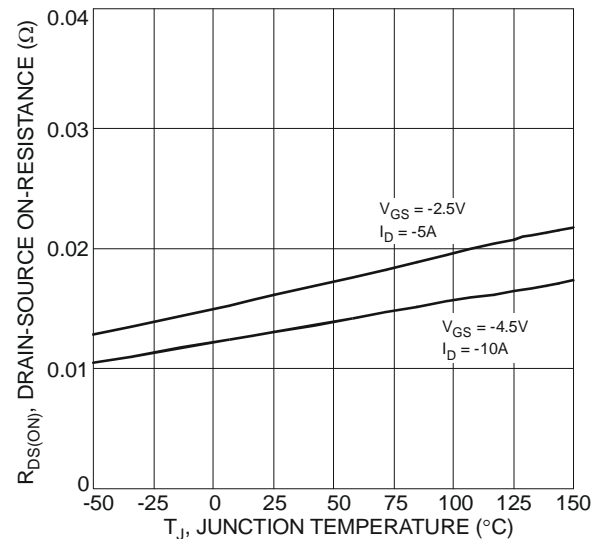


Fig. 9 On-Resistance Variation with Temperature

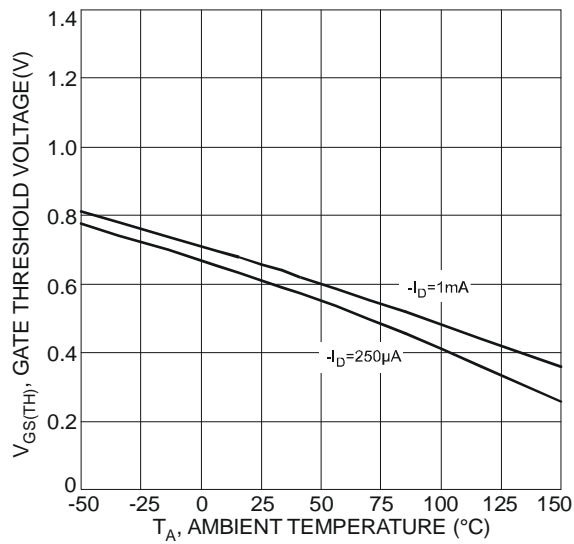


Fig. 10 Gate Threshold Variation vs. Ambient Temperature

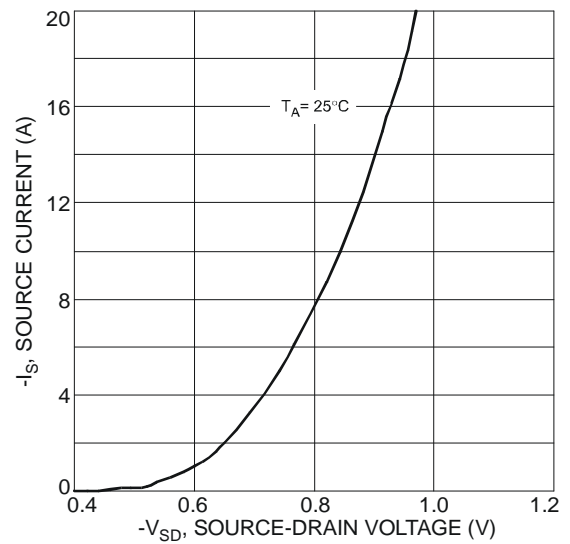


Fig. 11 Diode Forward Voltage vs. Current

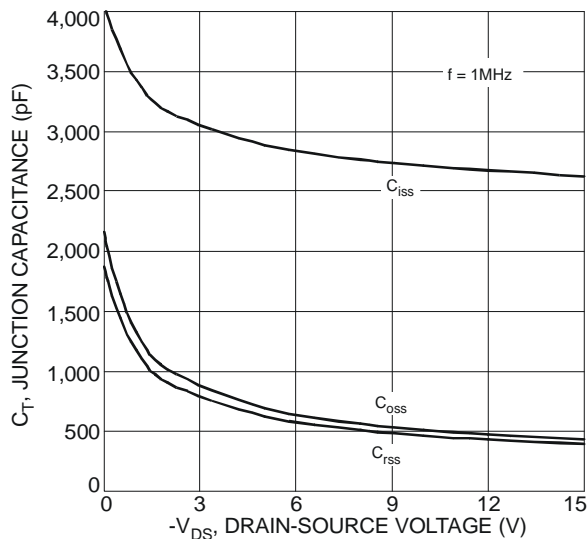


Fig. 12 Typical Junction Capacitance

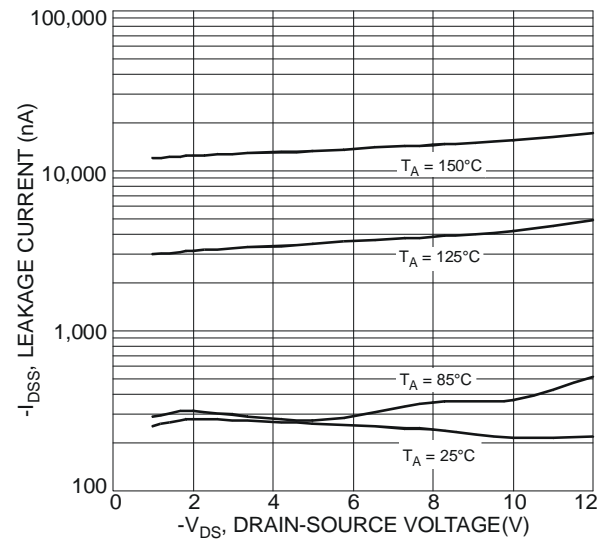


Fig. 13 Typical Drain-Source Leakage Current vs. Voltage

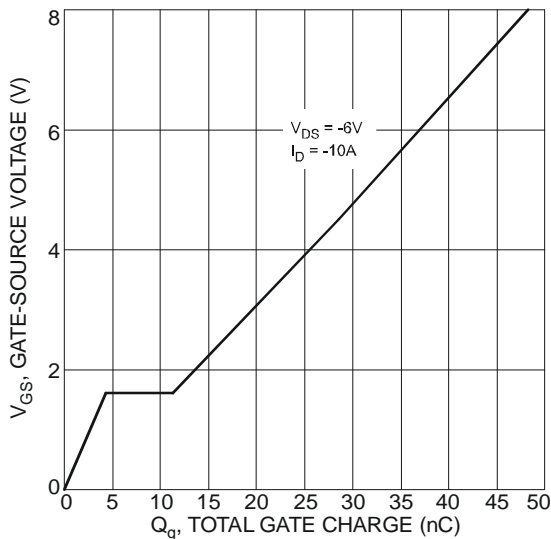
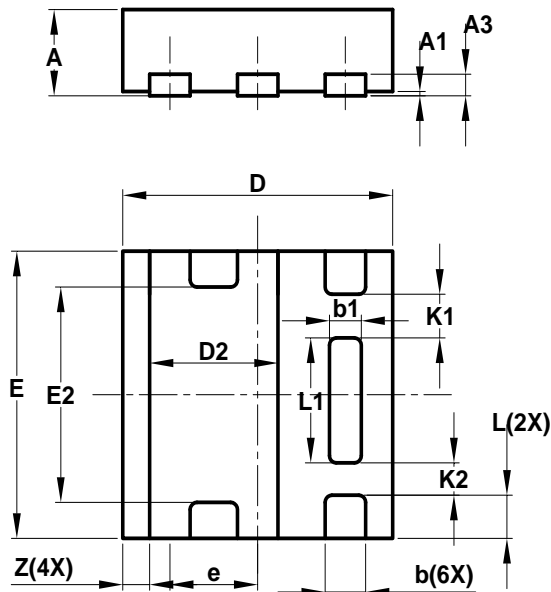


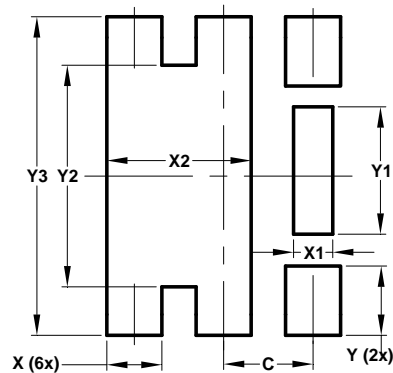
Fig. 14 Gate-Charge Characteristics

## Package Outline Dimensions



U-DFN2020-6 Type E			
Dim	Min	Max	Typ
A	0.57	0.63	0.60
A1	0	0.05	0.03
A3	—	—	0.15
b	0.25	0.35	0.30
b1	0.185	0.285	0.235
D	1.95	2.05	2.00
D2	0.85	1.05	0.95
E	1.95	2.05	2.00
E2	1.40	1.60	1.50
e	—	—	0.65
L	0.25	0.35	0.30
L1	0.82	0.92	0.87
K1	—	—	0.305
K2	—	—	0.225
Z	—	—	0.20
All Dimensions in mm			

## Suggested Pad Layout



Dimensions	Value (in mm)
C	0.650
X	0.400
X1	0.285
X2	1.050
Y	0.500
Y1	0.920
Y2	1.600
Y3	2.300

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